TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC7SZ04F,TC7SZ04FU

#### Inverter

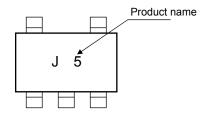
#### **Features**

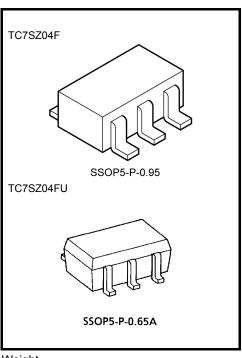
- High output drive: ±24 mA (min) at V<sub>CC</sub> = 3 V
- Super high speed operation: tpd=2.4 ns (typ.)

at  $V_{CC} = 5 \text{ V}$ , 50 pF

- Operation voltage range: V<sub>CC (opr)</sub> = 1.8~5.5 V
- 5.5-V tolerant inputs
- 5.5-V power down protection output
- Matches the performance of TC74LCX series when operated at 3.3- V V<sub>CC</sub>







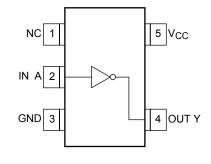
Weight

SSOP5-P-0.95 : 0.016 g (typ.) SSOP5-P-0.65A: 0.006 g (typ.)

### **Absolute Maximum Ratings (Ta = 25°C)**

Characteristics	Symbol	Rating	Unit
Supply voltage range	V <sub>CC</sub>	-0.5~6	V
DC input voltage	V <sub>IN</sub>	-0.5~6	V
DC output voltage	V <sub>OUT</sub>	-0.5~V <sub>CC</sub> + 0.5	V
Input diode current	I <sub>IK</sub>	-20	mA
Output diode current	I <sub>OK</sub>	±20	mA
DC output current	lout	±50	mA
DC V <sub>CC</sub> /ground current	Icc	±50	mA
Power dissipation	$P_{D}$	200	mW
Storage temperature	T <sub>stg</sub>	-65~150	°C
Lead temperature (10 s)	TL	260	°C

### Pin Assignment (top view)

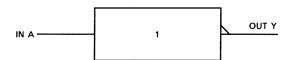


Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).



# **Logic Diagram**



### **Truth Table**

Α	Υ
L	Н
Н	L

# **Operating Ranges**

Characteristics	Symbol	Rating	Unit	
Supply voltage	V <sub>CC</sub>	1.8~5.5	V	
		1.5~5.5 (Note 1)	V	
Input voltage	V <sub>IN</sub>	0~5.5	V	
Output voltage	V <sub>OUT</sub>	0~5.5 (Note 2)	V	
		0~V <sub>CC</sub> (Note 3)	V	
Operating temperature	T <sub>opr</sub>	-40~85	°C	
	dt/dv	$0\sim20~(V_{CC}=1.8~V,~2.5~V\pm0.2~V)$	ns/V	
Input rise and fall time		$0 \sim 10 \; (V_{CC} = 3.3 \; V \pm 0.3 \; V)$		
		$0~5~(V_{CC} = 5.5~V \pm 0.5~V)$		

Note 1: Data retention only

Note 2:  $V_{CC} = 0 V$ 

Note 3: High or Low state

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### **Electrical Characteristics**

### **DC Characteristics**

Characteristics Symbol Test Condition			Ta = 25°C			Ta = -40~85°C		Unit		
		16	V <sub>CC</sub> (V)		Min	Тур.	Max	Min	Max	Offic
High-level input voltage VIH —		1.8	V <sub>CC</sub> × 0.88	_	_	V <sub>CC</sub> × 0.88	_	· V		
		2.3~5.5		V <sub>CC</sub> × 0.75	_	_	V <sub>CC</sub> × 0.75		_	
Low-level input	V			1.8	_		V <sub>CC</sub> × 0.12	ı	V <sub>CC</sub> × 0.12	· v
voltage	voltage V <sub>IL</sub>	_	2.3~5.5			V <sub>CC</sub> × 0.25		V <sub>CC</sub> × 0.25		
				1.8	1.7	1.8	_	1.7	_	
			I <sub>OH</sub> = -100 μA	2.3	2.2	2.3	_	2.2	_	
			ΙΟΗ = -100 μΑ	3.0	2.9	3.0	_	2.9	_	
High-level	V <sub>OH</sub>	V <sub>IN</sub> = V <sub>IL</sub>		4.5	4.4	4.5		4.4		V
output voltage	VOH	VIN - VIL	$I_{OH} = -8 \text{ mA}$	2.3	1.9	2.15		1.9		V
			I <sub>OH</sub> = -16 mA	3.0	2.4	2.8		2.4		
			I <sub>OH</sub> = -24 mA	3.0	2.3	2.68	_	2.3	_	
			I <sub>OH</sub> = -32 mA	4.5	3.8	4.2		3.8		
			100	1.8	_	0	0.1		0.1	
				2.3	_	0	0.1		0.1	
		I <sub>OL</sub> = 100 μA	3.0	_	0	0.1	_	0.1		
Low-level	Va	V <sub>IN</sub> = V <sub>IL</sub>		4.5	_	0	0.1		0.1	\
output voltage V <sub>OL</sub> V <sub>IP</sub>	VIN = VIL	I <sub>OL</sub> = 8 mA	2.3	_	0.1	0.3	_	0.3	V	
		I <sub>OL</sub> = 16 mA	3.0	_	0.15	0.4	_	0.4		
		I <sub>OL</sub> = 24 mA	3.0	_	0.22	0.55		0.55		
		I <sub>OL</sub> = 32 mA		_	0.22	0.55		0.55		
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = 5.5 \	V <sub>IN</sub> = 5.5 V or GND		_		±1		±10	μΑ
Power off leakage current	loff	V <sub>IN</sub> or V <sub>OUT</sub> = 5.5 V		0.0	_	_	1	_	10	μΑ
Quiescent supply current	Icc	V <sub>IN</sub> = V <sub>CC</sub> or GND		5.5	_	_	2	_	20	μА

### AC Characteristics (unless otherwise specified, Input: $t_r = t_f = 3$ ns)

Characteristics	Cumbal	Test Condition		Ta = 25°C		Ta = -40~85°C		Unit	
	Symbol		V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	Offic
Propagation delay time	t <sub>р</sub> LH t <sub>р</sub> HL	$\begin{array}{c} C_L = 15 \text{ pF}, \\ R_L = 1 \text{ M}\Omega \end{array}$	1.8	2.0	4.4	9.5	2.0	10.0	- ns
			$2.5 \pm 0.2$	0.8	2.9	6.5	0.8	7.0	
			$3.3 \pm 0.3$	0.5	2.1	4.5	0.5	4.7	
			$5.0 \pm 0.5$	0.5	1.8	3.9	0.5	4.1	
		$C_L = 50 \text{ pF},$ $R_L = 500 \Omega$	$3.3 \pm 0.3$	1.5	2.9	5.0	1.5	5.2	
			$5.0 \pm 0.5$	0.8	2.4	4.3	0.8	4.5	
Input capacitance	C <sub>IN</sub>	_	0~5.5	_	4	_	_		pF
Power dissipation capacitance	C <sub>PD</sub>	(Note 4)	3.3	_	20	_	_	_	- pF
			5.5		26		_		

Note 4: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

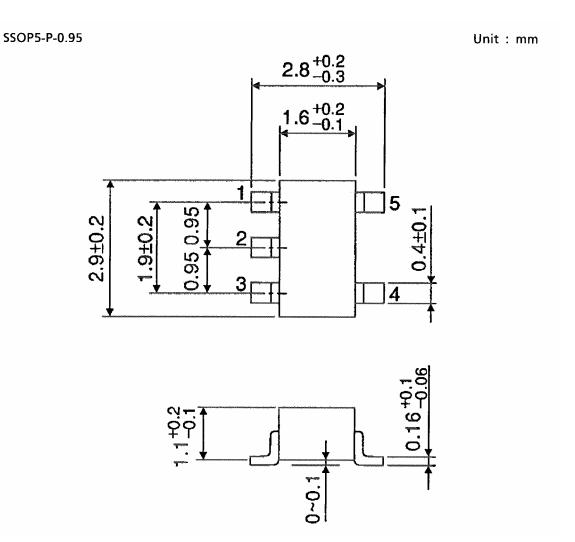
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Average operating current can be obtained by the equation:

 $I_{CC (opr.)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$ 



# **Package Dimensions**



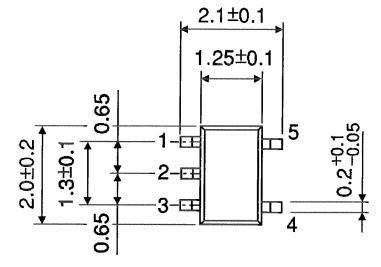
Weight: 0.016 g (typ.)

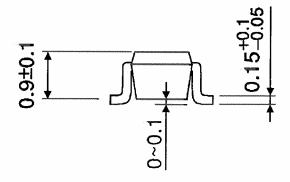
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# **Package Dimensions**

SSOP5-P-0.65A Unit: mm





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Weight: 0.006 g (typ.)

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20070701-EN GENERAL

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